Abstracts

Characterization of multiconductor coupled lines from multiport TDR measurements

A. Tripathi and V.K. Tripathi. "Characterization of multiconductor coupled lines from multiport TDR measurements." 1997 MTT-S International Microwave Symposium Digest 3. (1997 Vol. III [MWSYM]): 1777-1780.

A new procedure to characterize nonuniform coupled multiconductor lines based on a one dimensional peeling algorithm is presented. The measured multiport reflection (scattering parameter) parameters in the time domain are used to construct piece-wise uniform configuration oriented models for multiple coupled lines. Examples of nonuniform two and three coupled striplines are included to illustrate the technique.

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